

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes
For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory IECQ Certificate No.: IECQ-L ULTW 09.0023-05

CB Certificate No.: T1130-6

Schedule Number: IECQ-L ULTW 09.0023-S Rev No.: 3 Revision Date: 2017/12/12 Page 1 of 1

Appendix-1 (T1130-6)

Schedule of Scope to Certificate of Approval

Description test	Standard	Remark
Low Temperature Operation	IEC 60068-2-1	Or customer specified test conditions
Low Temperature Storage	IEC 60068-2-1	Or customer specified test conditions
High Temperature Operation	IEC 60068-2-2	Or customer specified test conditions
High Temperature Storage	IEC 60068-2-2	Or customer specified test conditions
High Temperature & High Humidity Operation	IEC 60068-2-3	Or customer specified test conditions
High Temperature & High Humidity Storage	IEC 60068-2-3	Or customer specified test conditions
Temperature Cycling	IEC 60068-2-14	Or customer specified test conditions
Thermal shock	IEC 60068-2-14	Or customer specified test conditions
Vibration (Sine wave)	IEC 60068-2-6	Or customer specified test conditions
Vibration (Random)	IEC 60068-2-34	Or customer specified test conditions
Mechanical Shock	IEC 60068-2-27	Or customer specified test conditions
Packing Vibration	ASTM D4728-06	Or customer specified test conditions

Technical Reviewer of DQS: Michael Chou Date: 11/17/2017

US-NAI, ECCC T.R.C.C. sign: Date: Nov. 20, 2017

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